

Lecture and Lab #2

Characterization of Spectral output of Light Source

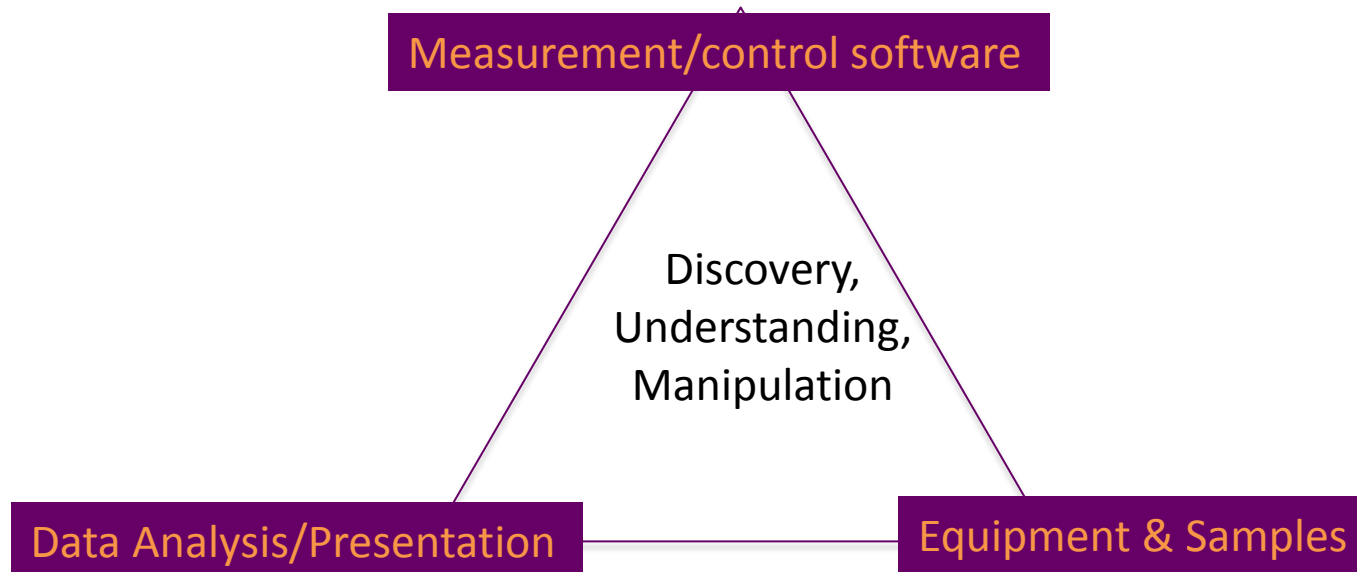
R.J. Ellingson and M.J Heben

August 27, 2013

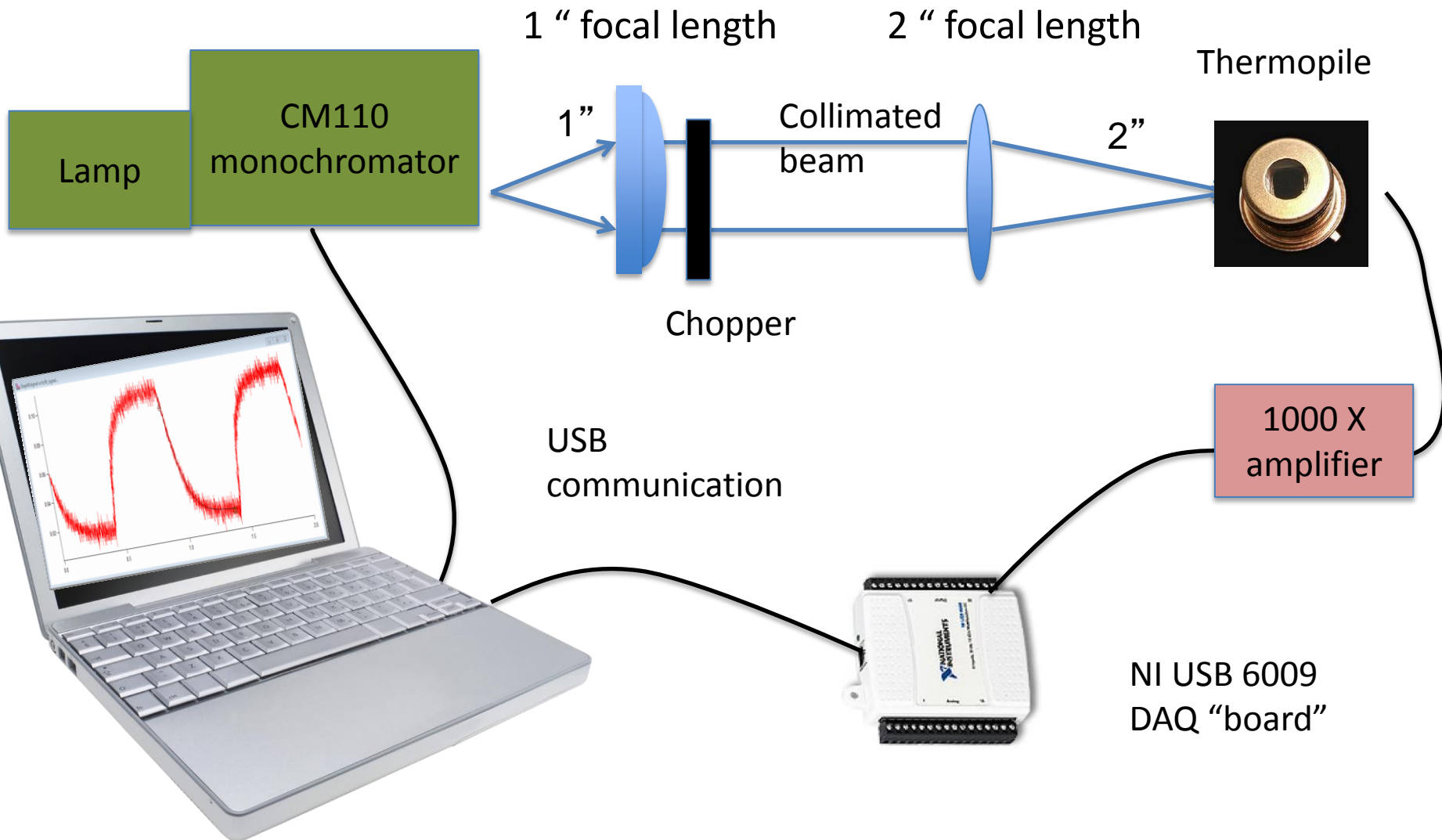
PHYS 4580, 6280, and 7280

Last week

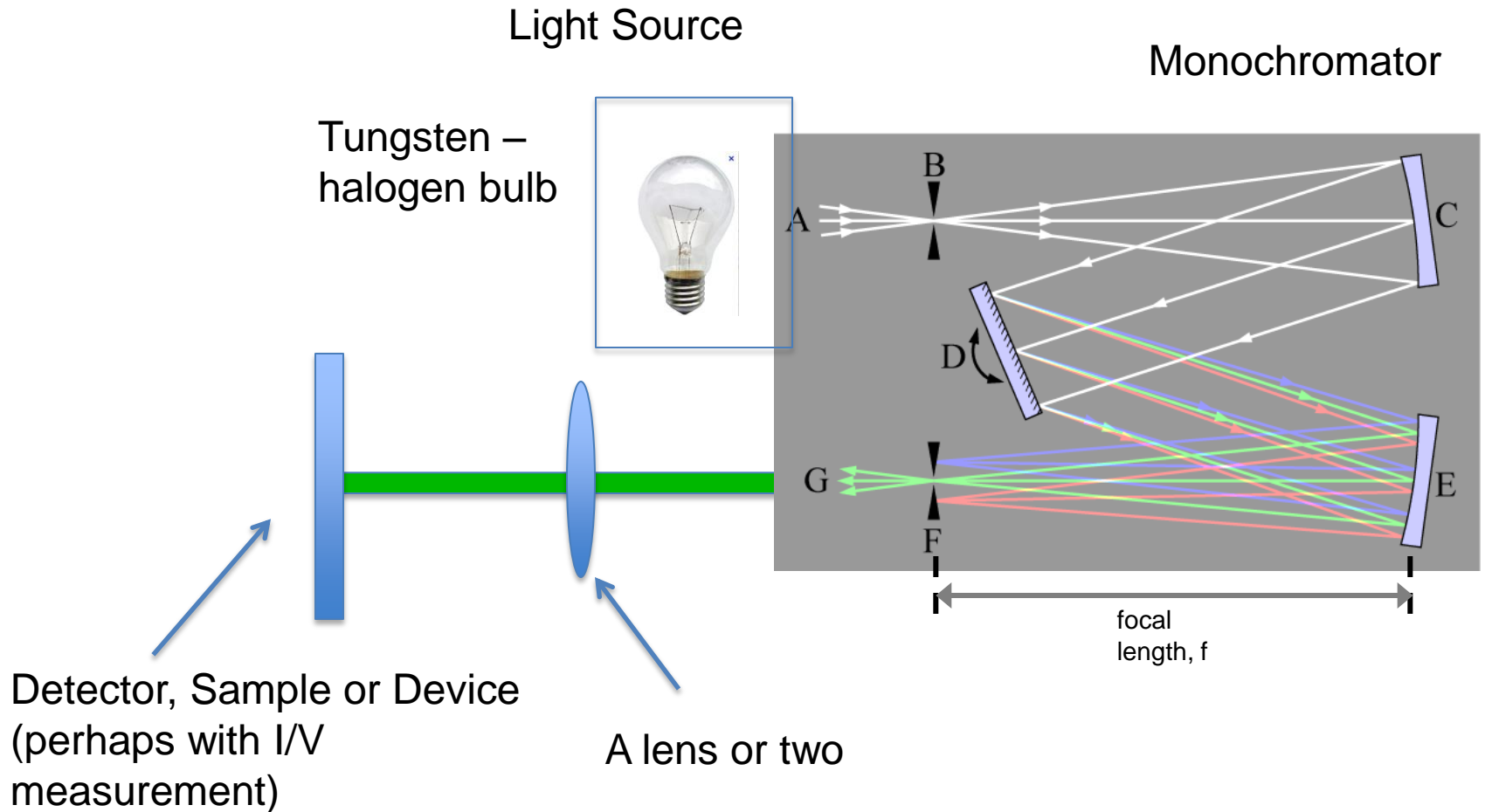
- Exercise to introduce students to:
 - LabVIEW (Measurement/control)
 - Igor Pro (Analysis/Presentation)
 - Optical measurement experimental Set-up.
- Time constant of Thermopile Detector



Response time of the thermopile (at one wavelength)



The “Set-Up”



Samples – semiconductor layers, transparent conductive layers, PV devices
Detectors – calibrated thermopile, photodiode

Thermopile Detector

A thermopile is an electronic device that **converts thermal energy into electrical energy**. It is composed of several thermocouples connected usually in series or, less commonly, in parallel.

Thermopiles do not respond to absolute temperature, but generate an output voltage proportional to a local temperature difference or temperature gradient.

Thermopiles are often used to provide a voltage output in response to temperature as part of a temperature measuring device, such as the infrared thermometers widely used by medical professionals to measure body temperature. They are also used widely in heat flux sensors. The output of a thermopile is usually in the range of tens or hundreds of millivolts.

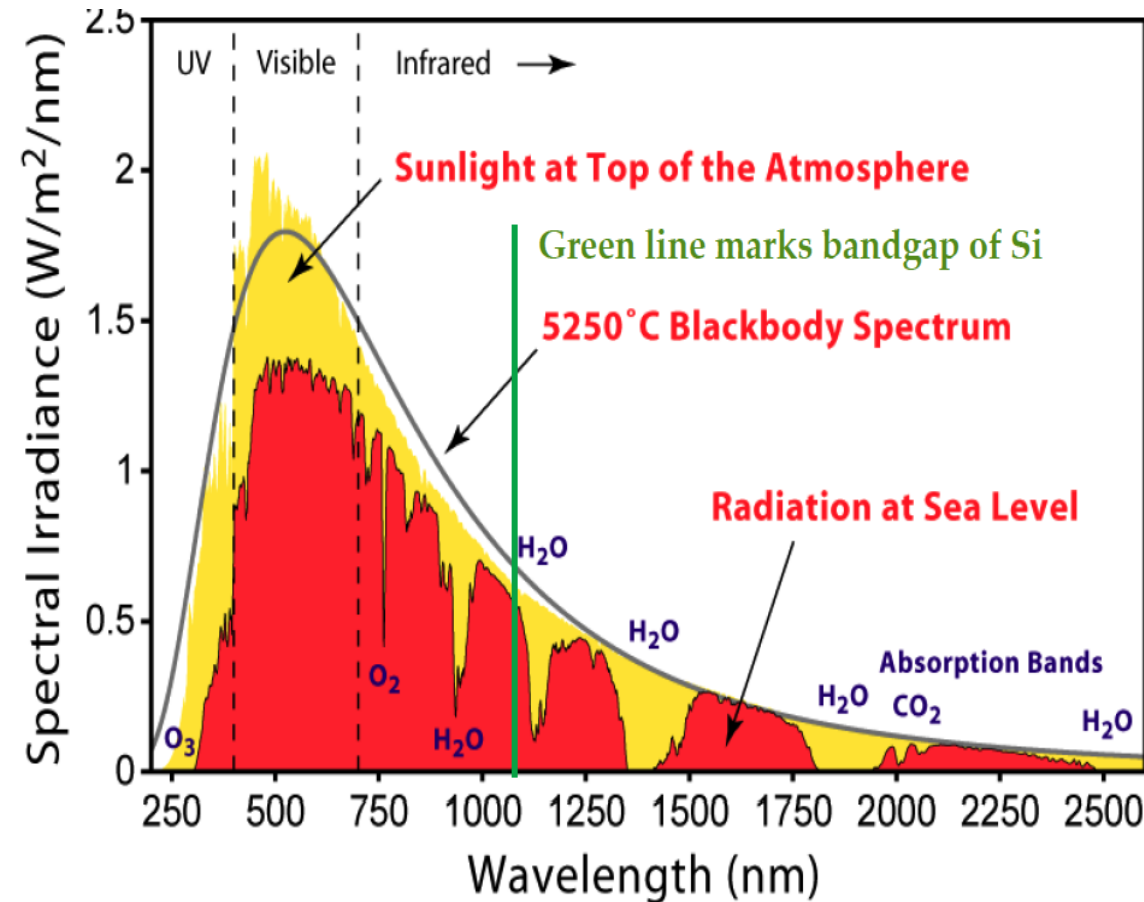
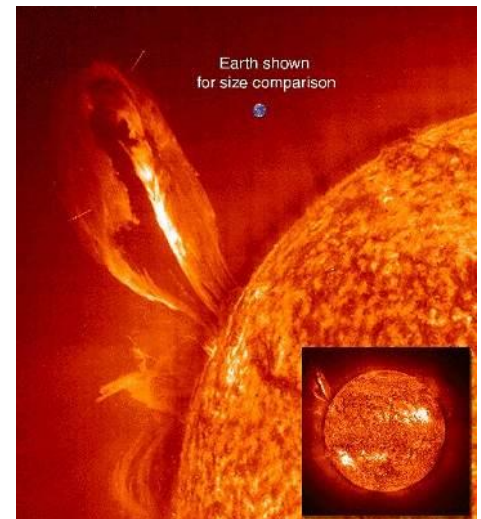
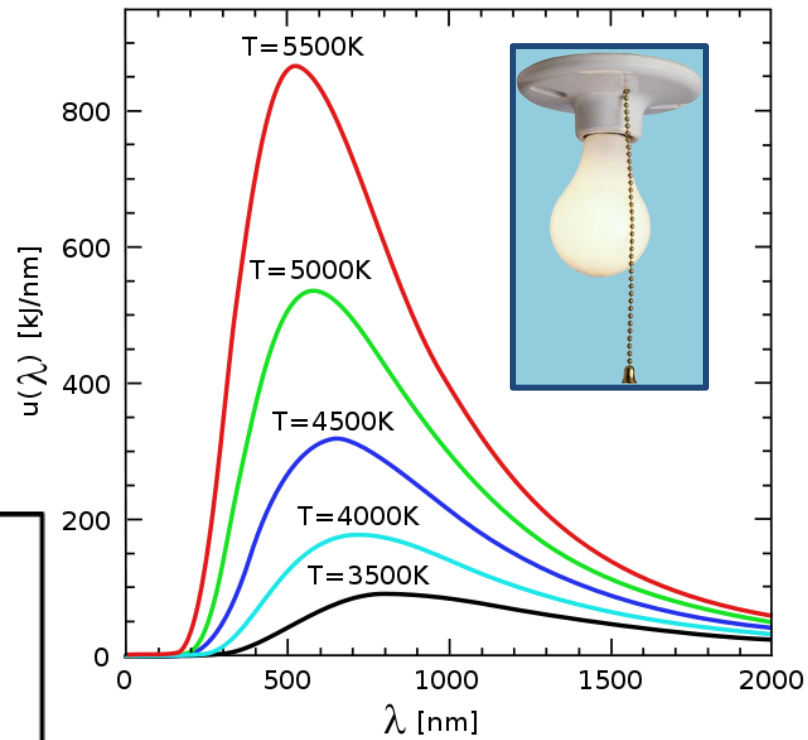


Dexter 2M detector

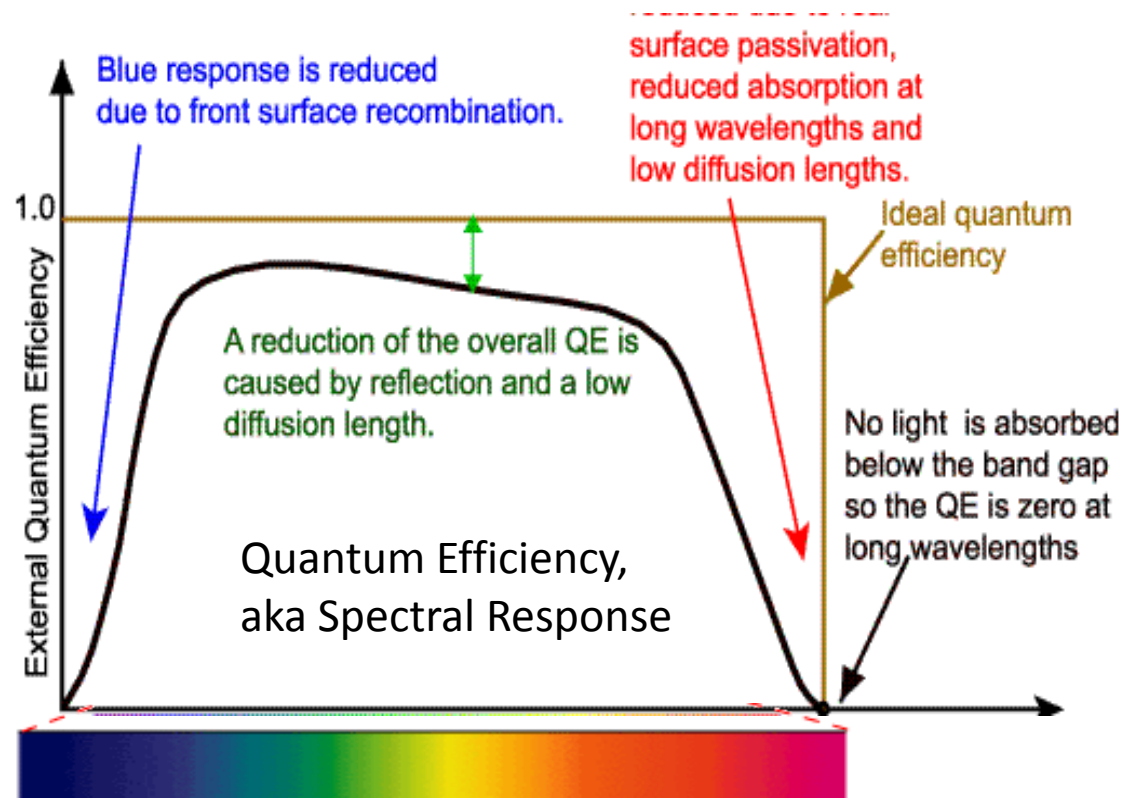
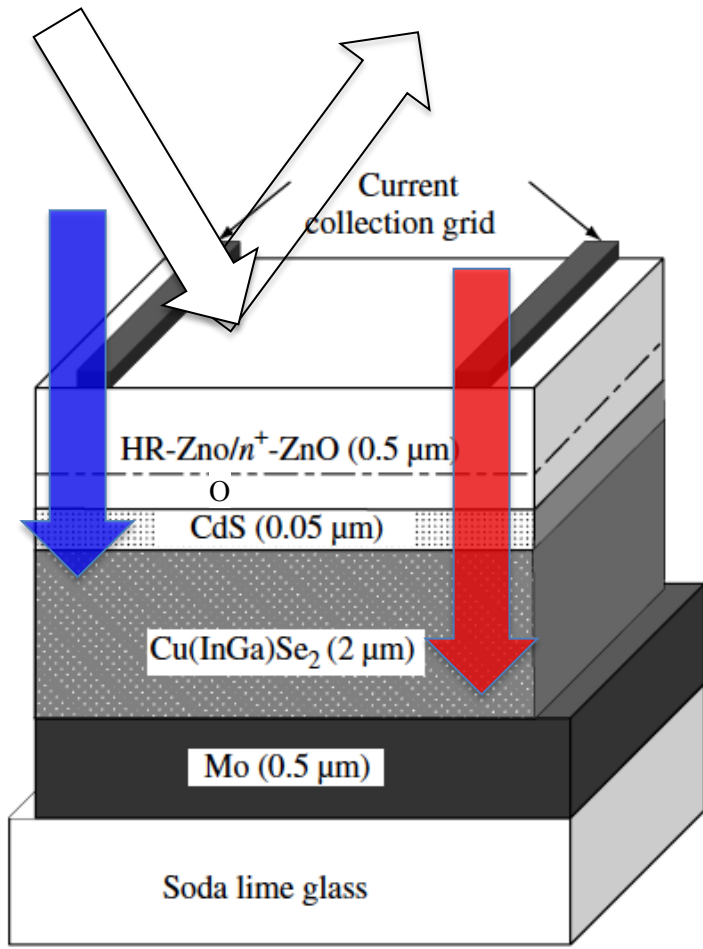


After Wikipedia and Dexter Research

Our Sun, and other Blackbody light sources, emit more than one wavelength of light.



Wavelength Dependent Response of PV Materials and Devices



Schematic cross section of a typical Cu(InGa)Se₂ solar cell

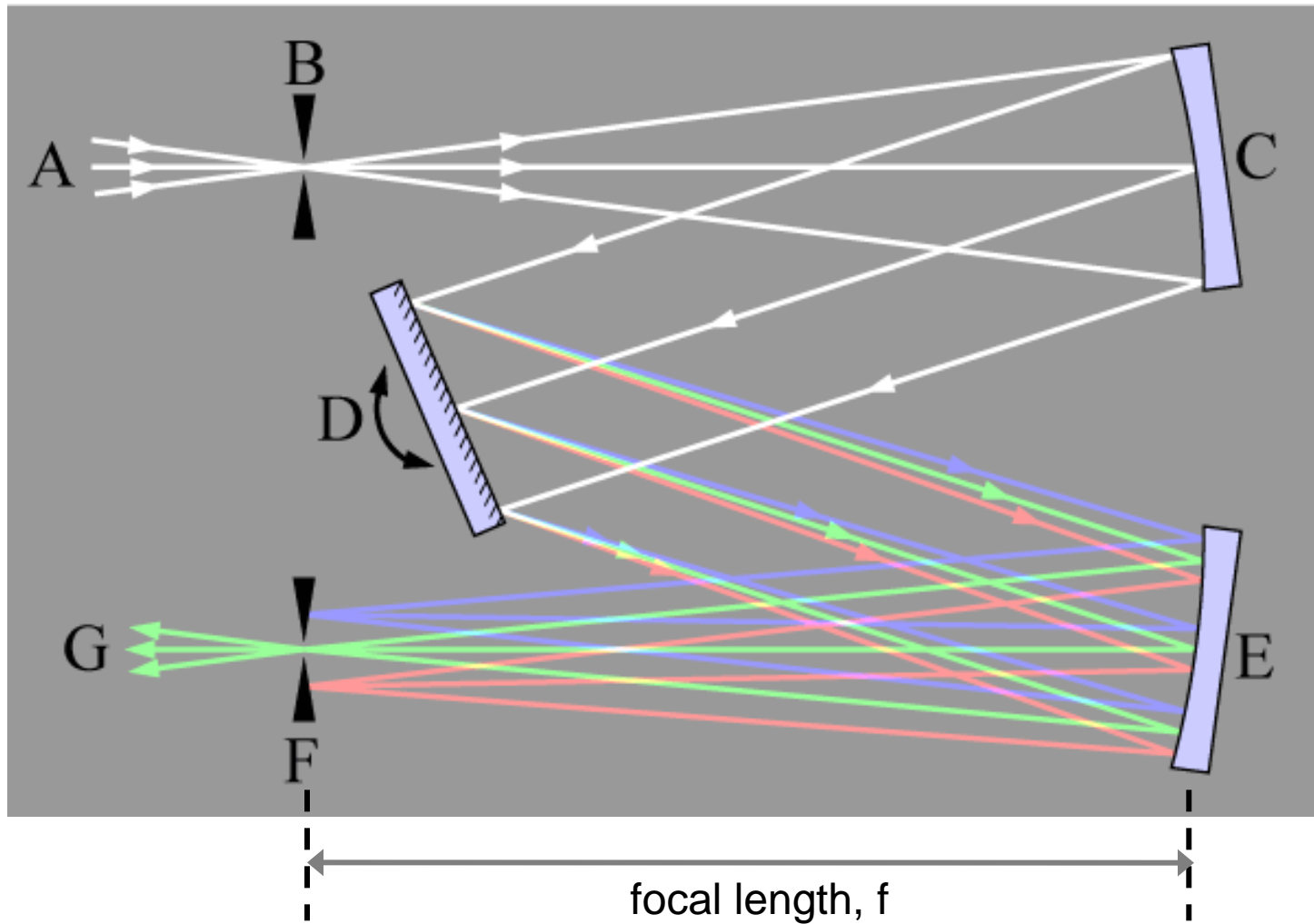
Spectral Products, CM110 1/8th meter monochromator



Feature	Value
Design:	Czerny-Turner, dual-grating turrets
Focal Length:	110mm
f/#:	3.9
Beam Path:	Straight through standard, right angle provided on request.
Wavelength Drive:	Worm and wheel with microprocessor control and anti-backlash gearing. Bi-directional. Usable in positive or negative grating orders.
Wavelength Precision:	0.2nm
Wavelength Accuracy:	± 0.6nm
Slewing Speed:	>100nm/second
Stray Light:	<10 ⁻⁵
Slits:	Standard Set includes; 0.125mm, 0.15mm, 0.30mm, 0.6mm, 1.2mm and 2.4mm x 4.0mm. For other sizes, consult SP.
Max Resolution:	<1nm w/1200G/mm grating and standard slits
Gratings:	One to two gratings. (30 x 30mm) must be purchased. See Appendix A for options
Software:	Demonstration control program and LabView driver included.
Power:	UL listed 110/220V power pack
Interface:	RS232 standard
Warranty:	One year
Options:	<ul style="list-style-type: none"> • Hand-held control module with function keys and display for local control • IEEE-488 interface • Interface cables • Gold optics <p>See options and accessories</p>

Serial commands sent from computer to CM110 via USB

Czerny-Turner Monochromator



Constructive Interference and the Grating Equation

$$m\lambda = d (\sin\alpha + \sin\beta); \text{ or } Gm\lambda = \sin\alpha + \sin\beta$$

Where m is the diffraction order and $G = 1/d$ is the groove frequency or density

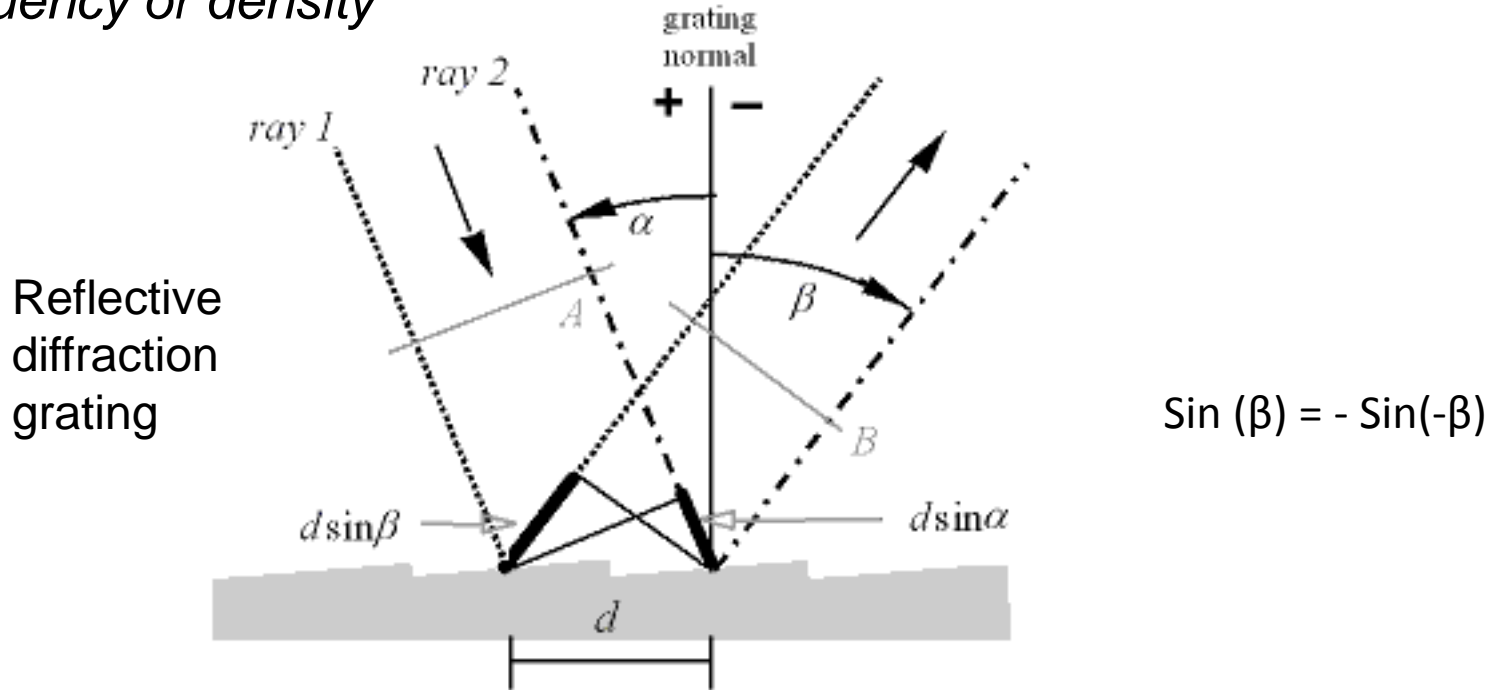


Figure 2-2. Geometry of diffraction, for planar wavefronts. Two parallel rays, labeled 1 and 2, are incident on the grating one groove spacing d apart and are in phase with each other at wavefront A. Upon diffraction, the principle of constructive interference implies that these rays are in phase at diffracted wavefront B if the difference in their path lengths, $d \sin\alpha + d \sin\beta$, is an integral number of wavelengths; this in turn leads to the grating equation.

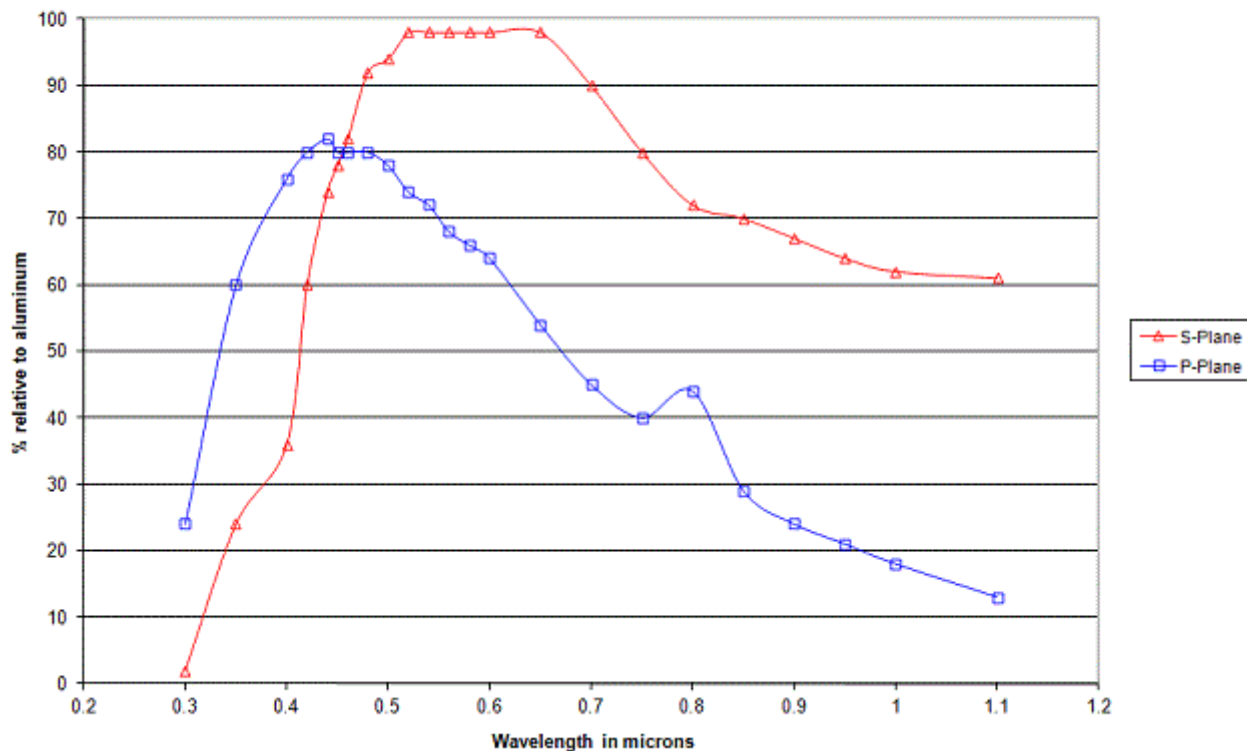
DIFFRACTION GRATING SPECIFICATION SHEET

Catalog no.	53-* -280R		8/27/2013
Grating Description	1200 g/mm plane ruled reflection grating with 17.5° nominal blaze angle		
Master no.	1597		
Maximum Ruled Area:		groove length:	154 mm
		ruled width:	206 mm

Efficiency Curve	spectral order:	m = 1	polarization(s):	S and P
	Coating:	aluminum		
Remarks				

Diffraction Grating Efficiency

1597-1, 1200 g/mm, 500 nm, 17.5 deg., M=1, Cat# 53-* -280, Plane ruled, Max RA 154 x 206 mm



Reciprocal Linear Dispersion (RLD)

Light dispersed at the output slit of the monochromator will show a linear dispersion of wavelengths with position across the slit.

Notice that when you are using the largest 2.4 mm slits, that when you set the monochromator wavelength to 500 nm, the output looks more blue on one end (shorter wavelengths), and more yellow on the other side (longer wavelengths).

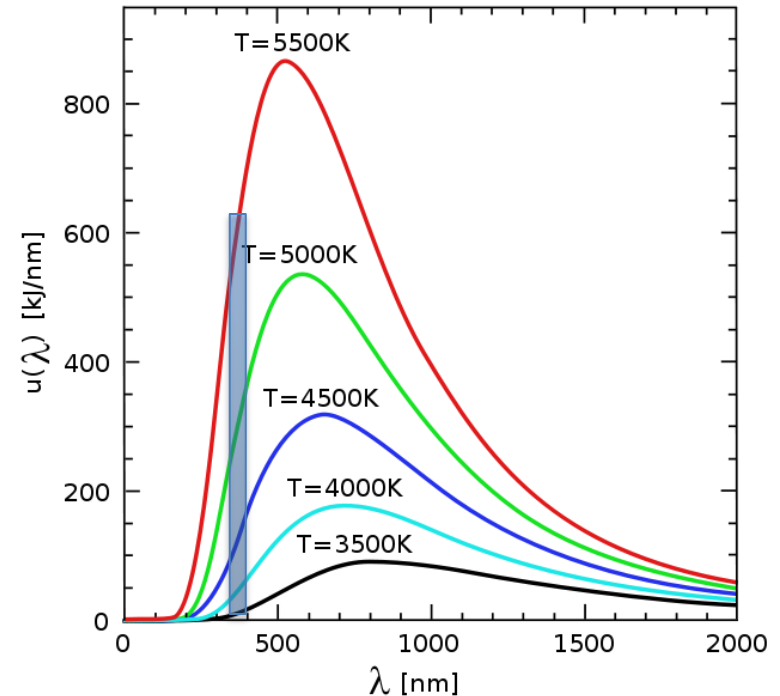
For the CM 110 monochromator, the RLD is 6.52 nm/mm.

Therefore, when using the 0.15 mm slits, the spectral band pass of the CM 110 is:

$$\Delta\lambda = (6.52 \text{ nm/mm}) * 0.15 \text{ mm} = 0.978 \text{ nm}$$

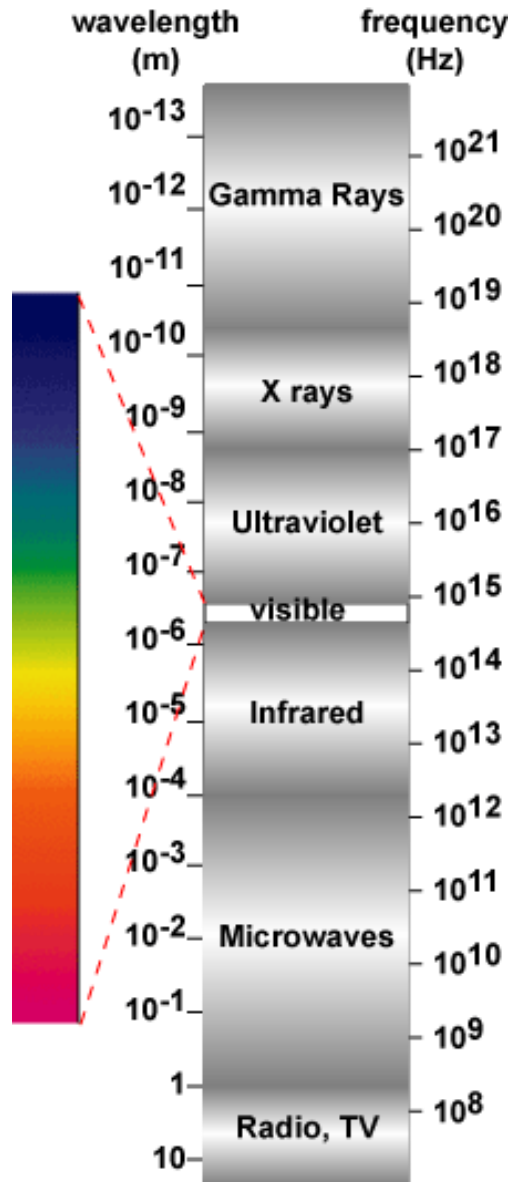
This Lab - Characterize Combined lamp/monochromator output at the sample (detector) location

- Single measurements as $f(\lambda)$
- Step through wavelengths
- Also a function of the slit-width:
 - Smaller slits, less photons
 - Larger slits, more photons



Question: How many Watts (or Joules, or Photons/s)/nm are incident at the sample plane (i.e. the detector)?

Photon Energy and Photon Flux



Thermopile measure Watts:

$$1 \text{ W} = 1 \text{ J/s} = 6.24 \times 10^{18} \text{ eV/s}$$

Energy of a photon: $E = \frac{hc}{\lambda}$

Convenient relation: $E = \frac{1.24}{\lambda(\mu\text{m})}$ (E in eV)

Definition of photon flux: $\Phi = \frac{\# \text{ of photons}}{\text{sec } m^2}$

Spectral irradiance can be expressed in units of:

W/($m^2 \cdot \text{nm}$)

or eV/($s \cdot m^2 \cdot \text{nm}$)

or # of photons/($s \cdot m^2 \cdot \text{nm}$)

Where:

- The m^2 term refers to area on which the photons are incident (we will neglect this term for now).
- The nm term refers to the bandpass width (which depends on the slit width).

LabVIEW Training Videos

<http://www.ni.com/academic/students/learn/>